Search Notes

Application No.	Applicant(s)	
09/599,783	FURUKAWA ET AL.	
Examiner	**Art Unit**	
Julio J. Maldonado	2823	

SEARCHED

Class	Subclass	Date	Examiner
438	717, 719, 734, 736, 738, 942,	5/8/2004	JJM
438	945, 950	5/8/2004	JJM
438	951	5/8/2004	JJM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East (USPAT; USPGPUB) pattern$3 with silicon with (substrate or wafer) with germanium and (hardmask "hard mask")	5/8/2004	JJM
germanium with anodic with oxidation	5/8/2004	JJM